Subminiature **Photointerrupter** 

(Unit: mm)

# GP2S09/GP2S24/ GP2S26/GP2S27

#### ■ Features

1. Compact and thin

**GP2S09**: Compact DIP long lead type

**GP2S24**: Compact DIP type GP2S26: Flat lead type

GP2S27: Mini-flat package type

■ Applications

1. Cassette tape recorders, VCRs

2. Floppy disk drives

3. Various microcomputerized control equip-

3. Visible light cut-off type **■** Outline Dimensions **GP2S09** GP2S24

2. Optimum detection distance: 0.6 to 0.8mm

0.4) Detector center **Emitter** center Emitter cente 3.0 + 0.2 (4.0) $\theta: 0 \text{ to } 20^{\circ}$ θ: 0 to 20° \*Tolerance:± 0.15mm \*Tolerance:±0.15mm \*( ): Reference dimensions Reference dimensions

**GP2S26 GP2S27** 0.4) Detector center Detector center (0.2) Emitter center 13.0<sup>±</sup> 1.0 olerance:±0.15mm Reference dimensions

\*The dimensions indicated by # refer to those measured from the lead base.

> \*Tolerance: ± 0.15mm \*( ): Reference dimensions

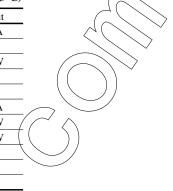
\*The dimensions indicated by \* refer

to those measured from the lead base.

Internal connection diagram (Common to 4 models) നം Anode 2 Emitter 3 Collector Cathode

### **Absolute Maximum Ratings**

■ Absolute Maximum Ratings (Ta = 25°C)					
	Parameter	Symbol	Rating	Unit	
Input	Forward current	$I_{\mathrm{F}}$	50	mA	
	Reverse voltage	V <sub>R</sub>	6	V	
	Power dissipation	P	75	mW	
Output	Collector-emitter voltage	V <sub>CEO</sub>	35	V	
	Emitter-collector voltage	V <sub>ECO</sub>	6	V	
	Collector current	Ic	20	mA	
	Collector power dissilpation	Pc	75	mW /	
	Total power dissipation	P <sub>tot</sub>	100	mW	
	Operating temperature	T <sub>opr</sub>	- 20 to + 85	°C	
	Storage temperature	T stg	- 40 to + 100	°C	
	*1Soldering temperature	T <sub>sol</sub>	260	°C	



\*1 Within 5 seconds (Soldering areas for each model are shown below )

#### GP2S09, GP2S24

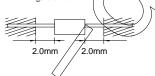
Soldering area: The hatched area more than 1mm\*2 away from the lower edge of package as shown in the figure below.



\*2 GP2S09: 4mm

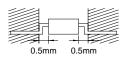
#### **GP2S26**

Soldering area: The hatched area more than 2.0mm away from the both edges of package as shown in the figure below.



#### **GP2S27**

Soldering area The hatched area more than 0.5mm away from the both edges of package as shown in the figure below.



## **■** Electro-optical Characteristics

$(Ta = 25^{\circ}C)$				
MAX.	Unit			

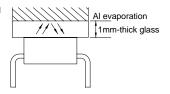
Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Forward voltage		VĘ	$I_F = 20 \text{mA}$	-	1.2	1.4	V
Reverse current	^	I <sub>R</sub>	$V_R = 6V$	-	-	10	μΑ
Collector dark curre	ent	ICEO	$V_{CE} = 20V$	-	10-9	10 -7	A
*3Collector current	~	$/I^{c}$	$I_F = 4mA$ , $V_{CE} = 2V$	20	45	120	μΑ
Response time	Rise time	$\searrow_{t_r}$	$V_{CE} = 2V, I_{C} = 100 \mu A$	-	20	100	μs
	Fall time	tf	$R_L = 1k\Omega$ , $d = 1mm$	-	20	100	μs
*4Leak current		ILEAK	$I_F = 4mA$ , $V_{CE} = 2V$	-	-	0.1	μΑ
	Forward voltage Reverse current Collector dark curre *3Collector current Response time	Forward voltage  Reverse current  Collector dark current  *3Collector current  Response time  Fall time	Forward voltage  Reverse current  Collector dark current  *3Collector current  Response time  Rise time  Fall time  tr	Forward voltage $ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$

<sup>\*3</sup> The condition and arrangement of the reflective object are shown below.

The ranking of collector current shall be class fied into the following 6 ranks. (GP2S09, GP2S24, GP2\$26, GP2\$27

Rank	Collector-current $I_{\mathfrak{C}}(\mu A)$
*5A	/20.to.42
В	34107]
С	58 to 120
A or B	20 to 71
B or C	34 to 120
A, B or C	20 to 120

**Test Condition and** Arrangement for **Collector Current** 



<sup>\*4</sup> Without reflective object

<sup>\*5</sup> GP2S24 and GP2S26 and GP2S27 don't have A rank.



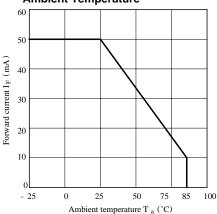


Fig. 3 Forward Current vs. Forward Voltage

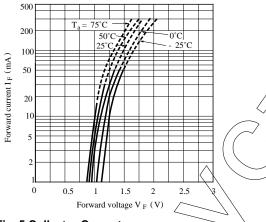


Fig. 5 Collector Current vs.
Collector-Emitter Voltage

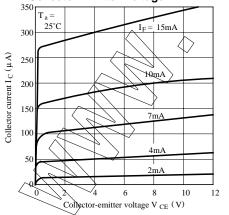


Fig. 2 Power Dissipation vs.
Ambient Temperature

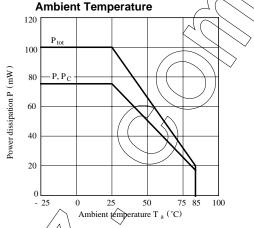


Fig. 4 Collector Current vs. Forward Current

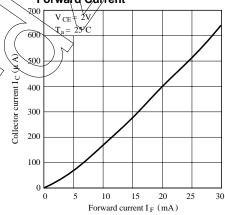
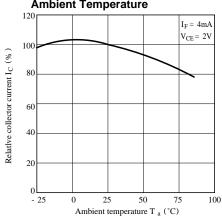


Fig. 6 Relative Collector Current vs.

Ambient Temperature



(GP2S09)

2 5 10

 $I_F = 4mA$ 

 $V_{CE} = 2V$ 

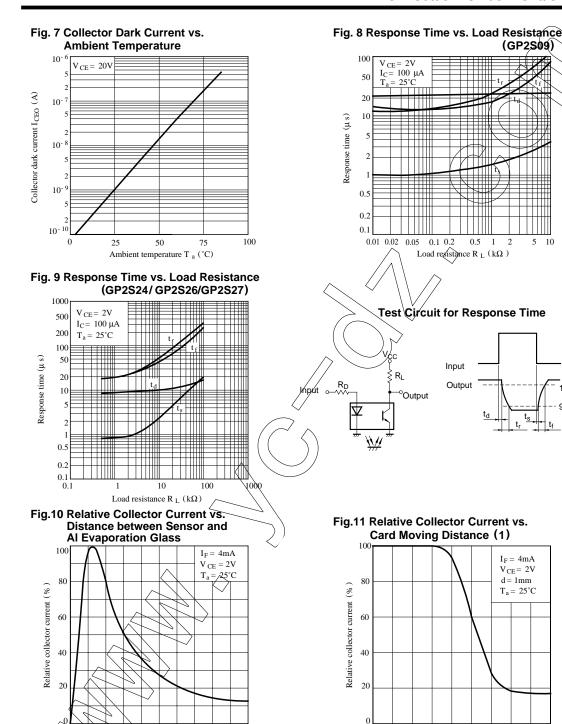
d = 1mm

 $T_a = 25^{\circ}C$ 

2 3 4 5 6

Card moving distance L (mm)

90%



2

3

Distance between sensor and Al evaporation glass d (mm)

2 3 4 5

Card moving distance L (mm)

Fig.13-a Frequency Response (GP2S09)

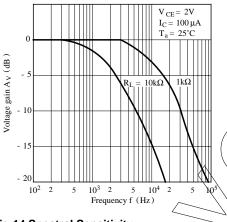
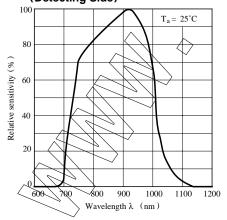
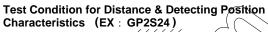


Fig.14 Spectral Sensitivity (Detecting Side)





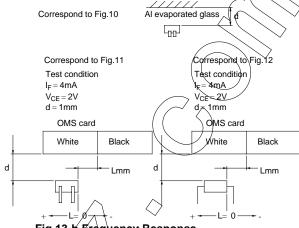
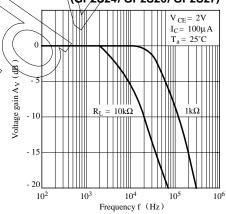


Fig.13-b Frequency Response (GP2S24/ GP2S26/ GP2S27)



• Please refer to the chapter "Precautions for Use".

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- Alarm equipment
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